




# TEST REPORT

|  |  |   |
|--|--|---|
| FCC ID..... :                          | OKUBS2909A   |   |
| Test Report No..... :                  | TCT250609E006  |   |
| Date of issue..... :                   | Jul. 03, 2025  |   |
| Testing laboratory .....               | SHENZHEN TONGCE TESTING LAB  |   |
| Testing location/ address:             | 2101 & 2201, Zhenchang Factory, Renshan Industrial Zone, Fuhai Subdistrict, Bao'an District, Shenzhen, Guangdong, 518103, People's Republic of China |   |
| Applicant's name..... :                | Shenzhen Junlan Electronic Ltd   |   |
| Address..... :                         | No.277 PingKui Road, Shijing Community, Pingshan Office, Pingshan New District, Shenzhen, China  |   |
| Manufacturer's name ... :              | Shenzhen Junlan Electronic Ltd   |   |
| Address..... :                         | No.277 PingKui Road, Shijing Community, Pingshan Office, Pingshan New District, Shenzhen, China  |   |
| Standard(s) .....                      | KDB 447498 D01 General RF Exposure Guidance v06  |   |
| Product Name..... :                    | Key finder   |   |
| Trade Mark .....                       | Amazon Basics  |   |
| Model/Type reference..... :            | TTIF06A, BS-2909, B0CDLQ7ZL4, TTIF06XX (XX can be replaced by letter from "A" to "Z", number from "0" to "9" or blank.)                              |   |
| Rating(s)..... :                       | DC 3V  |   |
| Date of receipt of test item .....     | Jun. 09, 2025  |   |
| Date (s) of performance of test..... : | Jun. 09, 2025 ~ Jul. 03, 2025  |   |
| Tested by (+signature) ... :           | Ronaldo LUO  |  |
| Check by (+signature).... :            | Beryl ZHAO   |  |
| Approved by (+signature):              | Tomsin   |  |

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## 1. General Product Information

### 1.1. EUT description

|                            |                    |
|----------------------------|--------------------|
| Product Name.....:         | Key finder         |
| Model/Type reference.....: | TTIF06A            |
| Sample Number.....:        | TCT250609E005-0101 |
| Operation Frequency .....  | 433.92MHz          |
| Modulation Type .....      | FSK                |
| Antenna Type.....:         | FPC Antenna        |
| Antenna Gain.....:         | -2.22dBi           |
| Rating(s).....:            | DC 3V              |

Note: The antenna gain listed in this report is provided by applicant, and the test laboratory is not responsible for this parameter.

### 1.2. Model(s) list

| No.          | Model No.  | Tested with                         |
|--------------|--|-------------------------------------|
| 1            | TTIF06A  | <input checked="" type="checkbox"/> |
| Other models | BS-2909, B0CDLQ7ZL4, TTIF06XX (XX can be replaced by letter from "A" to "Z", number from "0" to "9" or blank.) | <input type="checkbox"/>            |

Note: TTIF06A is tested model, other models are derivative models. The models are identical in circuit and PCB layout, different on the model names. So the test data of TTIF06A can represent the remaining models.

## 2. General Information

### 2.1. Test environment and mode

| Item                  | Normal condition  |
|-----------------------|---|
| Temperature           | +25°C   |
| Voltage               | DC 3V   |
| Humidity              | 56%   |
| Atmospheric Pressure: | 1008 mbar   |
| Test Mode:            |   |
| Engineering mode:     | Keep the EUT in continuous transmitting by select channel |

### 2.2. Description of Support Units

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

| Equipment | Model No. | Serial No. | FCC ID | Trade Name |
|-----------|-----------|------------|--------|------------|
| /         | /         | /          | /      | /          |

**Note:**

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.
3. For conducted measurements (Output Power, 20dB Occupied Bandwidth, Carrier Frequencies Separation, Hopping Channel Number, Dwell Time, Spurious Emissions), the antenna of EUT is connected to the test equipment via temporary antenna connector, the antenna connector is soldered on the antenna port of EUT, and the temporary antenna connector is listed in the Test Instruments.

### 3. Facilities and Accreditations

#### 3.1. Facilities

The test facility is recognized, certified, or accredited by the following organizations:

- FCC - Registration No.: 645098

SHENZHEN TONGCE TESTING LAB

Designation Number: CN1205

The testing lab has been registered and fully described in a report with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files.

- A2LA-No.: 4320.01

SHENZHEN TONGCE TESTING LAB

The testing lab has been accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 General requirements for the competence of testing and calibration laboratories.

#### 3.2. Location

SHENZHEN TONGCE TESTING LAB

Address: 2101 & 2201, Zhenchang Factory, Renshan Industrial Zone, Fuhai Subdistrict, Bao'an District, Shenzhen, Guangdong, 518103, People's Republic of China

TEL: +86-755-27673339

## 4. Test Results and Measurement Data

According to KDB 447498 D01 General RF Exposure Guidance v06, systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the commission's guidance.

The 1-g SAR test exclusion thresholds :

- a) For 100 MHz to 6 GHz at test separation distances  $\leq 50$  mm are determined by:  
[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)]  $\cdot$  [ $\sqrt{f(\text{GHz})}$ ]  $\leq 3.0$  for 1-g SAR, where
- $f(\text{GHz})$  is the RF channel transmit frequency in GHz
  - Power and distance are rounded to the nearest mW and mm before calculation
  - When the minimum test separation distance is  $< 5$  mm, a distance of 5 mm according is applied to determine SAR test exclusion.
  - The result is rounded to one decimal place for comparison
- b) For 100 MHz to 6 GHz and test separation distances  $> 50$  mm, the 1-g test exclusion thresholds are determined by the following (also illustrated in Appendix B):
- 1) {[Power allowed at numeric threshold for 50 mm in step a)] + [(test separation distance – 50 mm)  $\cdot$  ( $f_{(\text{MHz})}/150$ )]} mW, for 100 MHz to 1500 MHz
  - 2) {[Power allowed at numeric threshold for 50 mm in step a)] + [(test separation distance – 50 mm)  $\cdot$  10]} mW, for  $> 1500$  MHz and  $\leq 6$  GHz
- c) For frequencies below 100 MHz, the following may be considered for SAR test exclusion (also illustrated in Appendix C):
- 1) For test separation distances  $> 50$  mm and  $< 200$  mm, the power threshold at the corresponding test separation distance at 100 MHz in step b) is multiplied by  $[1 + \log(100/f_{(\text{MHz})})]$
  - 2) For test separation distances  $\leq 50$  mm, the power threshold determined by the equation in c) 1) for 50 mm and 100 MHz is multiplied by  $\frac{1}{2}$

### SRD

| Frequency (MHz) | Electric field strength (dBuV/m)@3m | Max. Power (dBm) | Tune up Power (dBm) | Max. Tune up Power (dBm) | Max. Tune up Power (mW) | Test distance (mm) | Result | exclusion thresholds for 1-g SAR |
|-----------------|-------------------------------------|------------------|---------------------|--------------------------|-------------------------|--------------------|--------|----------------------------------|
| 433.92          | 77.76                               | -22.17           | -23 $\pm$ 1         | -22                      | 0.006                   | 5                  | 0.026  | 3.0                              |

Note: computational formula

$$\text{EIRP[dBm]} = \text{E[dB}\mu\text{V/m]} + 20 \log(d[\text{m}]) - 104.77;$$

$$\text{Max. Power} = \text{EIRP}-4.7;$$

Where E is the electric field strength in V/m; d is the measurement distance in meters (m); 4.7 is the appropriate maximum ground reflection factor for frequencies between 30 MHz and 1000 MHz

### Result:

Base on the calculation value, No SAR measurement is required.

\*\*\*\*\*END OF REPORT\*\*\*\*\*